



STV160NF02L

N-CHANNEL 20V - 0.0016Ω - 160A PowerSO-10

STripFET™ II POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STV160NF02L	20 V	< 0.0025 Ω	160 A

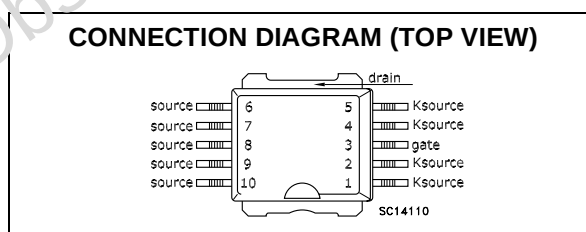
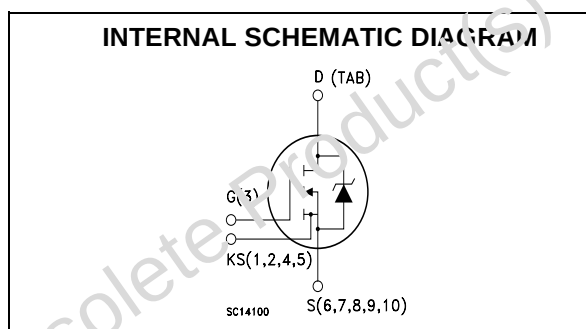
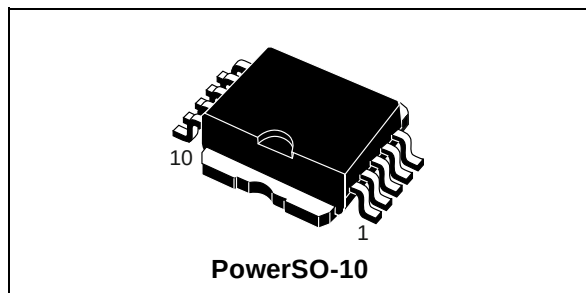
- TYPICAL R_{DS(on)} = 0.0016 Ω
- LOW THRESHOLD DRIVE
- ULTRA LOW ON-RESISTANCE
- ULTRA FAST SWITCHING
- 100% AVALANCHE TESTED
- VERY LOW GATE CHARGE
- LOW PROFILE, VERY LOW PARASITIC INDUCTANCE PowerSO-10 PACKAGE

DESCRIPTION

The **STV160NF02L** represents the second generation of Application Specific STMicroelectronics well established STripFET™ process based on a very unique strip layout design. The resulting MOSFET shows unrivalled high packing density with ultra low on-resistance and superior switching characteristics. Process simplification also translates into improved manufacturing reproducibility. This device is particularly suitable for high current, low voltage switching application where efficiency is crucial

APPLICATIONS

- BUCK CONVERTERS IN HIGH PERFORMANCE TELECOM AND VRMs DC-DC CONVERTERS



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	20	V
V _{DG}	Drain-gate Voltage (R _{GS} = 20 kΩ)	20	V
V _{GS}	Gate- source Voltage	± 15	V
I _D (**)	Drain Current (continuos) at T _C = 25°C	160	A
I _D	Drain Current (continuos) at T _C = 100°C	113	A
I _{DM} (●)	Drain Current (pulsed)	640	A
P _{TOT}	Total Dissipation at T _C = 25°C	210	W
	Derating Factor	1.4	W/°C
E _{AS} (1)	Single Pulse Avalanche Energy	1.5	J
T _{stg}	Storage Temperature	-65 to 175	°C
T _j	Max. Operating Junction Temperature	175	°C

(●) Pulse width limited by safe operating area

(1) Starting T_j=25°C , I_D = 80A, V_{DD} = 20V

(**)Limited only maximum junction temperature allowed by PowerSO-10

STV160NF02L**THERMAL DATA**

Rthj-case	Thermal Resistance Junction-case Max	0.71	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	50	°C/W
T _I	Maximum Lead Temperature For Soldering Purpose	300	°C

ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED)
OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 µA, V _{GS} = 0	20			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating, T _C = 125 °C			1 10	µA µA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 15 V			±100	nA

ON (1)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250µA	1			V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V, I _D = 80 A V _{GS} = 10 V, I _D = 45 A V _{GS} = 10 V, I _D = 20 A V _{GS} = 8 V, I _D = 80 A V _{GS} = 5 V, I _D = 40 A V _{GS} = 10 V, I _D =80 A; T _J = 175 °C V _{GS} = 8 V, I _D =80 A; T _J = 175 °C V _{GS} = 5 V, I _D =40 A; T _J = 175 °C	1.35	1.6 1.56 1.7 3.5	2.5 2.5 2.5 3.5 6 5.7 7 11.4	mΩ mΩ mΩ mΩ mΩ mΩ mΩ mΩ
I _{D(on)}	On State Drain Current	V _{DS} > I _{D(on)} × R _{DS(on)} max, V _{GS} = 10V	160			A

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _{fs} (1)	Forward Transconductance	V _{DS} > I _{D(on)} × R _{DS(on)} max, I _D = 80A		210		S
R _g	Gate resistance	V _{DS} = 0 V, f = 1 MHz, V _{GS} = 0		0.5		Ω
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 15 V, f = 1 MHz, V _{GS} = 0		4800 3000 680		pF pF pF
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 0 V, f = 1 MHz, V _{GS} = 0		7000 12300 4200		pF pF pF
L _S	Internal Source Inductance	From the Lead End (6mm from Package Body) to the Die Center		4		nH
L _D	Internal Drain Inductance		Not Available on Surface Mounting Package			

ELECTRICAL CHARACTERISTICS (CONTINUED)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 10\text{ V}$, $I_D = 80\text{ A}$		28		ns
t_r	Rise Time	$R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$ (see test circuit, Figure 3)		800		ns
Q_g	Total Gate Charge	$V_{DD} = 16\text{ V}$, $I_D = 160\text{ A}$, $V_{GS} = 10\text{ V}$		115	160	nC
Q_{gs}	Gate-Source Charge			15		nC
Q_{gd}	Gate-Drain Charge			45		nC

SWITCHING OFF

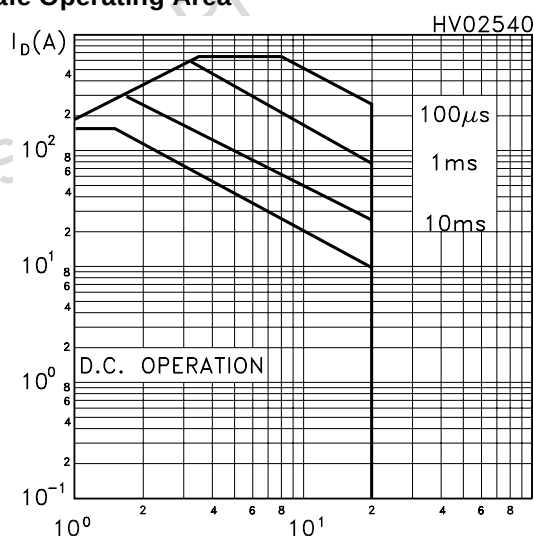
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$	Turn-off-Delay Time	$V_{DD} = 10\text{ V}$, $I_D = 80\text{ A}$, $R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$ (see test circuit, Figure 5)		80		ns
t_f	Fall Time			240		ns
$t_{d(off)}$	Turn-off Delay Time	$V_{clamp} = 16\text{ V}$, $I_D = 40\text{ A}$		80		ns
$t_{r(Voff)}$	Off-voltage Rise Time	$R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$		40		ns
t_f	Fall Time			140		ns
t_c	Cross-over Time			200		ns

SOURCE DRAIN DIODE

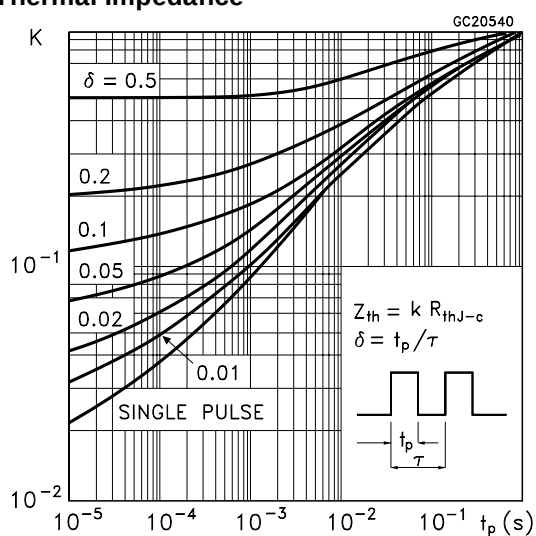
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain Current				160	A
$I_{SDM(1)}$	Source-drain Current (pulsed)				640	A
$V_{SD(2)}$	Forward On Voltage	$I_{SD} = 160\text{ A}$, $V_{GS} = 0$			1.5	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 80\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 15\text{ V}$, $T_j = 25^\circ\text{C}$ (see test circuit, Figure 5)		90		ns
Q_{rr}	Reverse Recovery Charge			225		nC
I_{RRM}	Reverse Recovery Current			5		A

Note: 1. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %.
2. Pulse width limited by safe operating area.

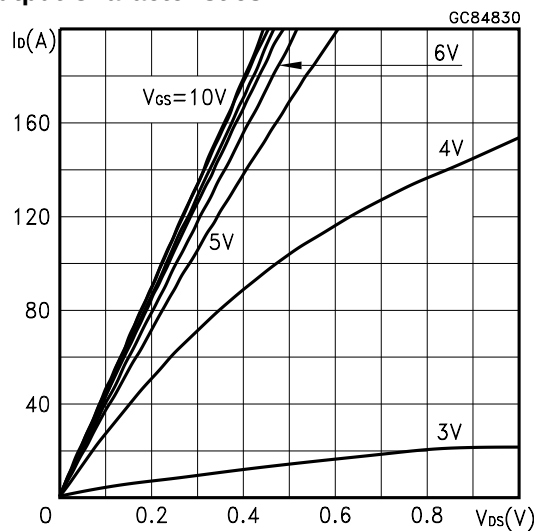
Safe Operating Area



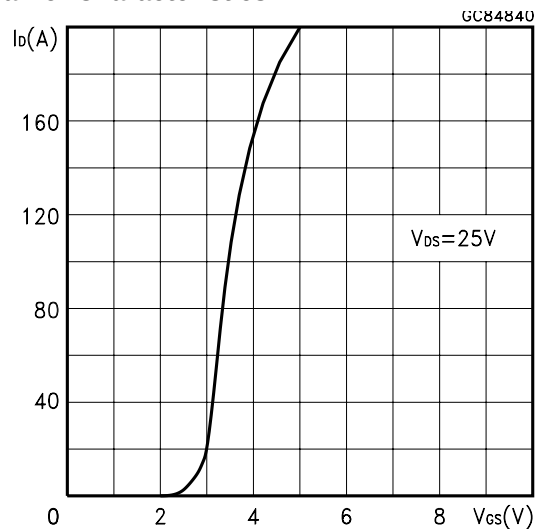
Thermal Impedance



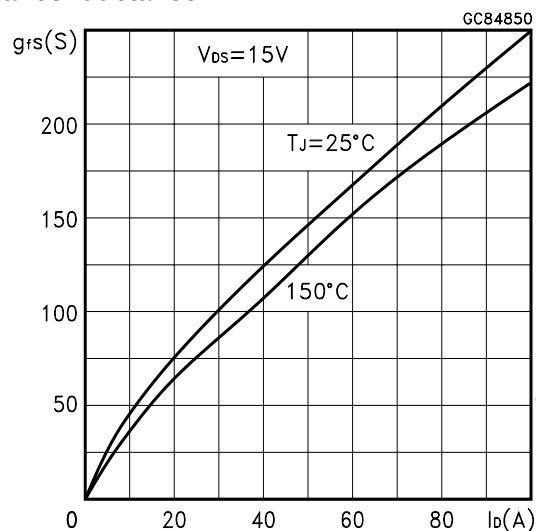
Output Characteristics



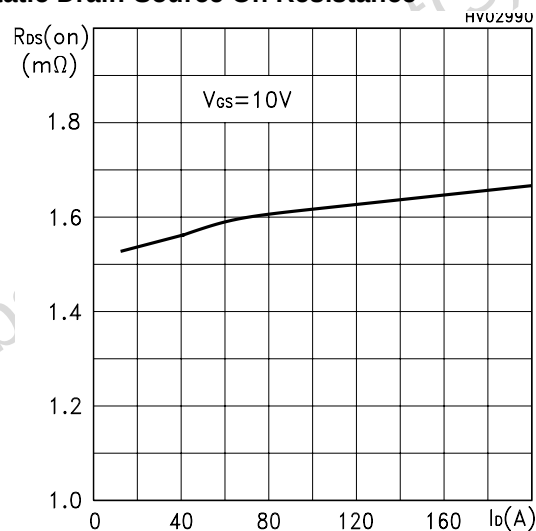
Transfer Characteristics



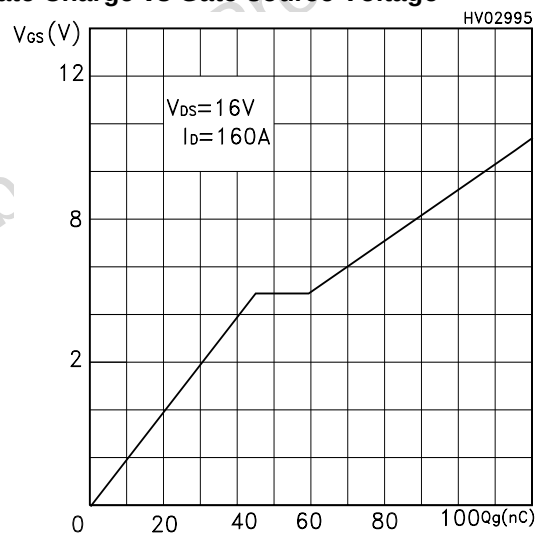
Transconductance



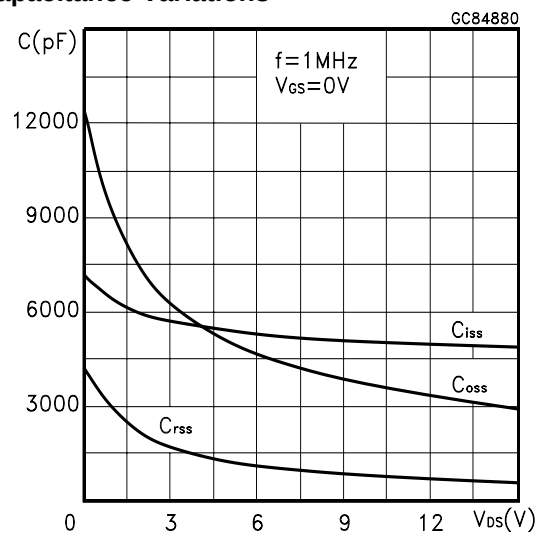
Static Drain-Source On Resistance



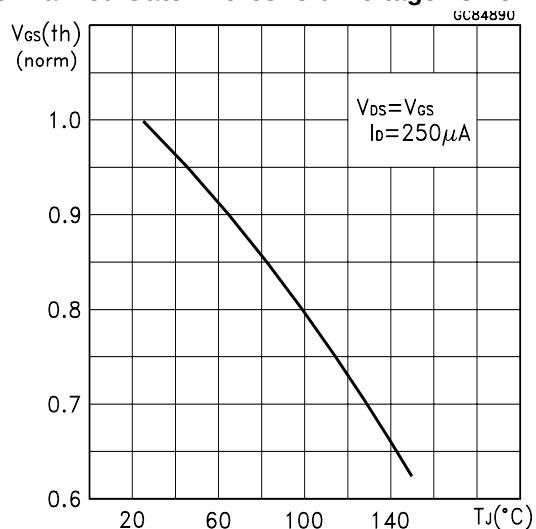
Gate Charge vs Gate-source Voltage



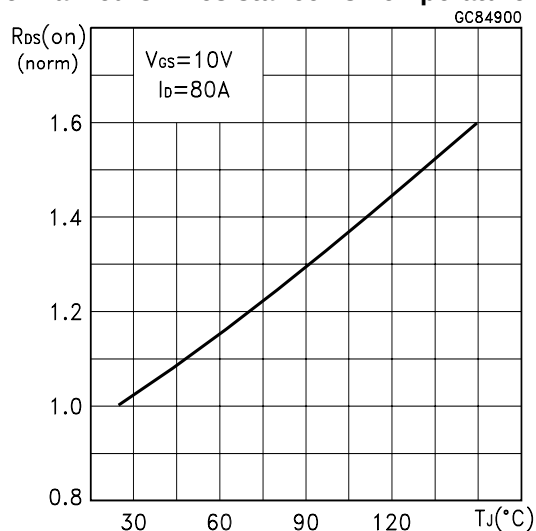
Capacitance Variations



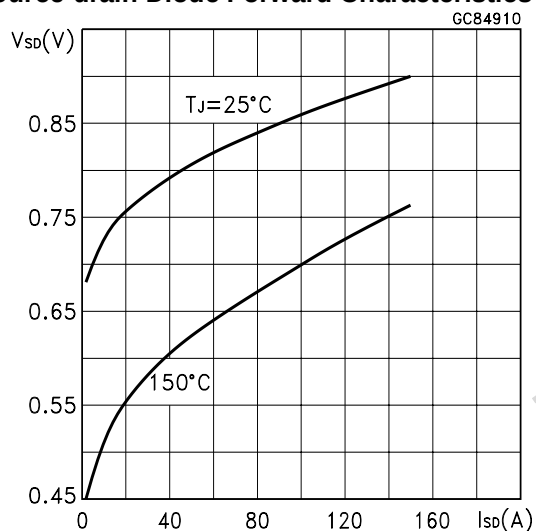
Normalized Gate Threshold Voltage vs Temp.



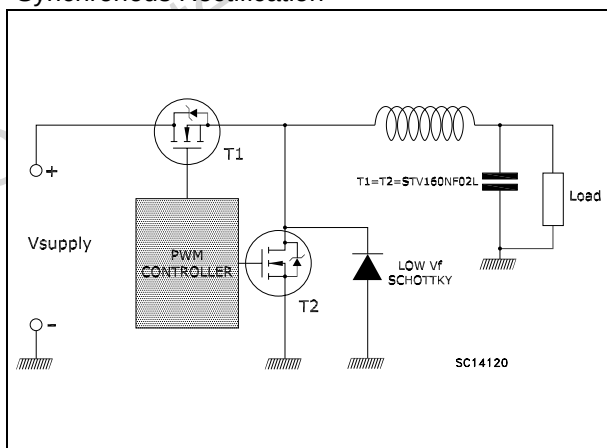
Normalized On Resistance vs Temperature



Source-drain Diode Forward Characteristics



Basic Schematic For Motherboard VRM With Synchronous Rectification



Basic Schematic Mosfets Switch Used In Secondary Side Of a Froward Convert

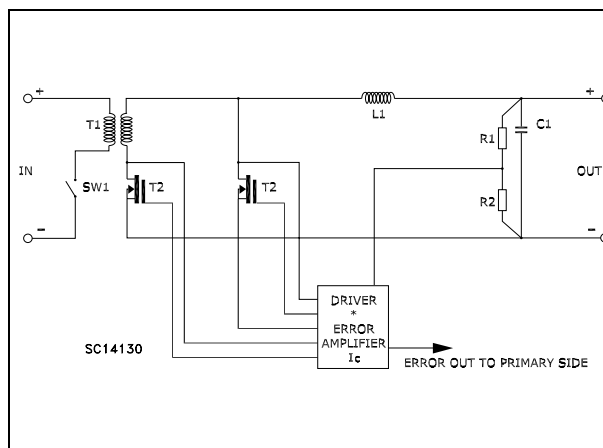


Fig. 1: Unclamped Inductive Load Test Circuit

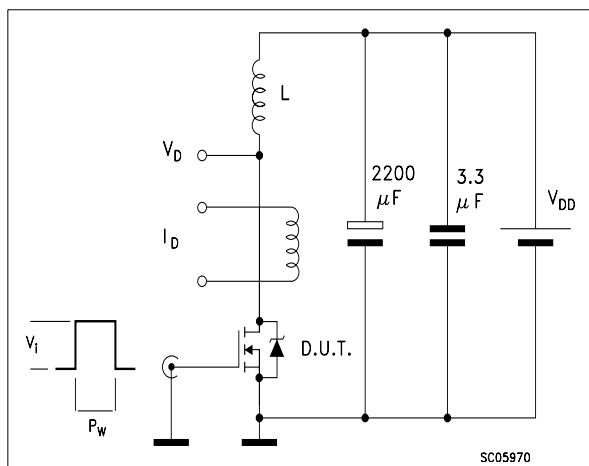


Fig. 2: Unclamped Inductive Waveform

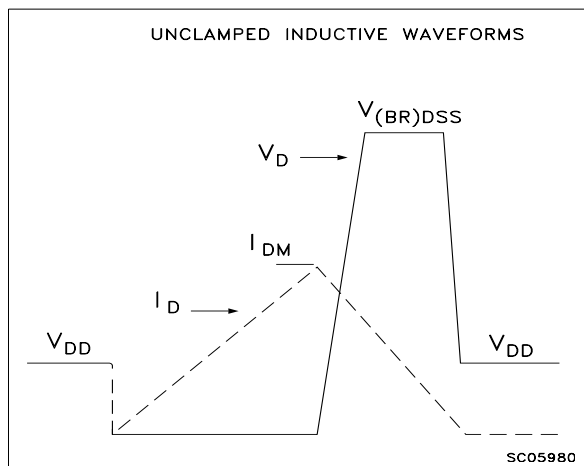


Fig. 3: Switching Times Test Circuit For Resistive Load

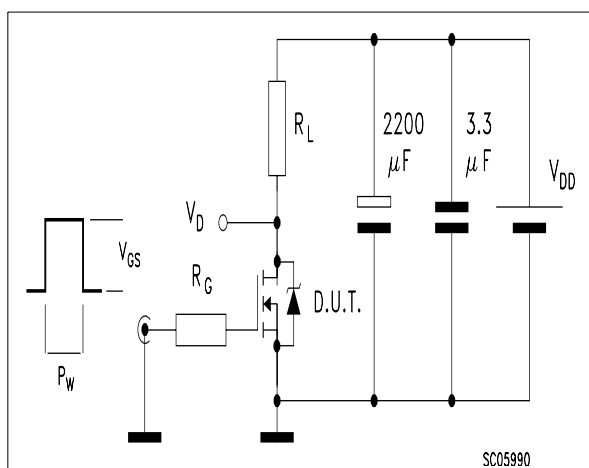


Fig. 4: Gate Charge test Circuit

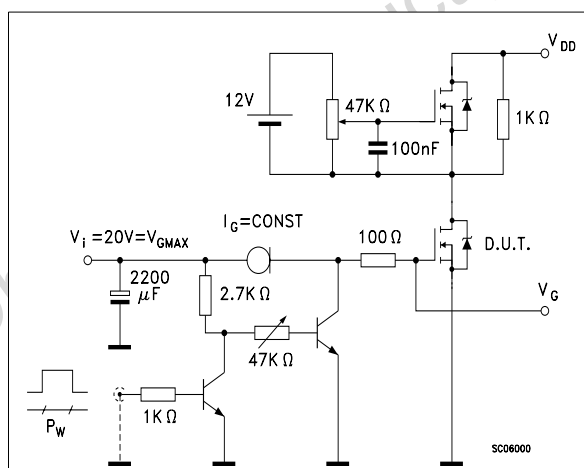
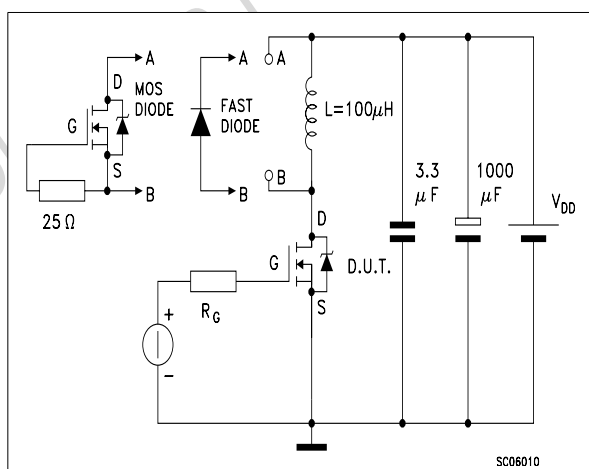
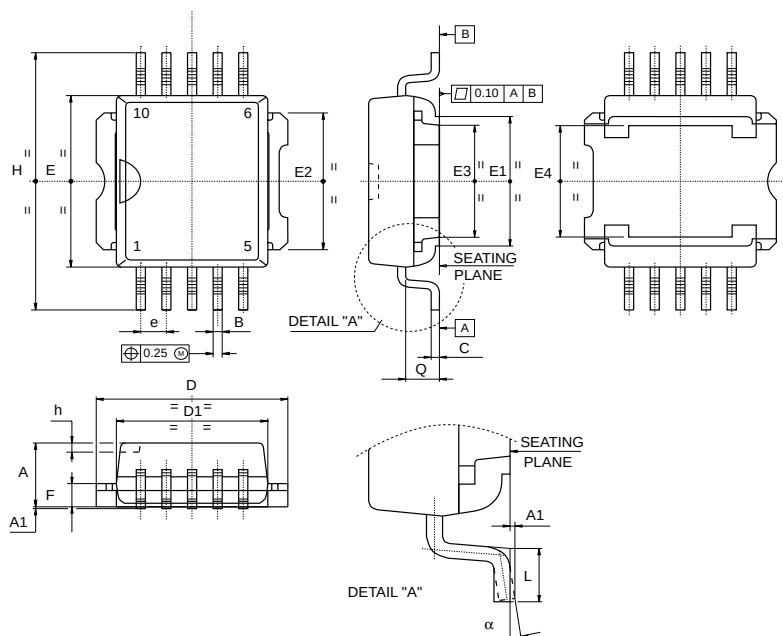


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



PowerSO-10 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	3.35		3.65	0.132		0.144
A1	0.00		0.10	0.000		0.004
B	0.40		0.60	0.016		0.024
C	0.35		0.55	0.013		0.022
D	9.40		9.60	0.370		0.378
D1	7.40		7.60	0.291		0.300
e		1.27			0.050	
E	9.30		9.50	0.366		0.374
E1	7.20		7.40	0.283		0.291
E2	7.20		7.60	0.283		0.300
E3	6.10		6.35	0.240		0.250
E4	5.90		6.10	0.232		0.240
F	1.25		1.35	0.049		0.053
h		0.50			0.002	
H	13.80		14.40	0.543		0.567
L	1.20		1.80	0.047		0.071
q		1.70			0.067	
α	0°		8°			



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